

Würth Elektronik eiSos GmbH &amp; Co. KG

EMC &amp; Inductive Solutions

Max-Eyth-Straße 1 · 74638 Waldenburg · Germany

Tel. +49 (0) 79 42 945-0 · Fax +49 (0) 79 42 945-400

eiSos@we-online.de · www.we-online.de



## Product/Process Change Notice (PCN)

- Major change  
 Minor change

PCN #: WE-MPSB\_20171201\_Capacity\_Increase

Product Affected: WE-MPSB

PCN Date: September 1st 2017

Effective Date: December 1st 2017

- Product Mark  
 Date Code  
 Packaging  
 Others

Contact: Product Management

Phone: +49 (0) 7942 - 945 5001

Fax: +49 (0) 7942 - 945 5179

E-mail: pcn.eisos@we-online.de

Attachment:  Yes  No

Samples:

### DESCRIPTION AND PURPOSE OF CHANGE:

In order to increase the production capacity of the Product Series WE-MPSB, Würth Elektronik will move parts from the production line of the affected part numbers indicated by the lot number starting with 241 xxx xxx xxx x0x to a new building.

### DETAIL OF CHANGE:

- Neither electrical nor mechanical properties of the part will change.
- Process & Machine approval is according to internal requirements released by the Quality Department and the Product Management Department.
- Affected part numbers:

#### WE-MPSB 0603

7427922808

74279228111

74279228260

74279228600

#### WE-MPSB 0805

74279220181

#### WE-MPSB 1206

74279221100

74279221111

- The status of the location change can be tracked by the lot number.  
241 xxx xxx xxx x0x will indicate a shipment from the current location.  
241 xxx xxx xxx x1x will indicate a shipment from the new location.

### RELIABILITY / QUALIFICATION SUMMARY:

After the complete movement is done the WE-MPSB, series will be verified by an internal WE-Reliability Test.

|    | Test                                | Qty  | Reference              | Test conditions   |
|----|-------------------------------------|------|------------------------|---|
| 1  | High Temperature Exposure (Storage) | 0/30 | MIL-STD-202 Method 108 | Preconditioning : 1 time lead-free Heat exposure<br>Temperature: 125±3°C*<br>Testing time: 500h Unpowered.<br>Measurement at 24±2 hours after test conclusion.  |
| 2  | Moisture Resistance                 | 0/30 | MIL-STD-202 Method 106 | Preconditioning : 1 time lead-free Heat exposure<br>Time/Cycle = 24 h; Temperature: 65±2°C<br>500h, Humidity: 95%, Unpowered.<br>Measurement at 24±2 hours after test conclusion.   |
| 3  | Operational Life                    | 0/30 | MIL-PRF-27             | Preconditioning : 1 time lead-free Heat exposure<br>Testing time: 1000h<br>Temperature: Ambient Temp. 85±5°C* + rated current = 125°C*<br>Measurement at 24±2 hours after test conclusion.  |
| 4  | Terminal Strength (SMD)             | 0/30 | internal spec.         | Preconditioning : Solder components on test board (lead-free)<br>Apply an individual force for 60 seconds. Please refer the attached table in the description below.  |
| 5  | Vibration                           | 0/30 | MIL-STD-202 Method 204 | Preconditioning : Solder components on test board (lead-free)<br>10g's for 20 minutes, 12 cycles each of 3 orientations.<br>Note: Use 8"X5" PCB, .031" thick, 7 secure points on one long side and 2 secure points at corners of opposite sides.<br>Parts mounted within 2" from any secure point.<br>Test from 15-2000 Hz. |
| 6  | Five Time Reflow                    | 0/30 | J-STD-020D             | Lead -free soldering profile:<br>Peak temperature according to table 4.2 of the J-STD-020   |
| 7  | Solderability                       | 0/30 | JESD22-B102            | For both Leaded & SMD. Electrical Test not required.<br>Magnification 50X. Conditions:<br>SMD: a) Method B, Steam Aging 4 hrs @ 98% r.H. @ 245°C  |
| 8  | Thermal Shock                       | 0/30 | MIL-STD-202 Method 107 | Preconditioning : 1 time lead-free Heat exposure<br>Temperature: -40°C/+125°C*<br>Dwell time is 30 minutes.<br>Cycles: 300 Transfer time max. 20s.  |
| 9  | Board Flex                          | 0/30 | AEC-Q200-005           | Preconditioning : Solder components on test board (lead-free)<br>Appendix 2 Note: 2mm (Min)<br>Sample size: 30  |
| 10 | Low Temperature Storage Life        | 0/30 | JESD22-A119            | Preconditioning : 1 time lead-free Heat exposure<br>Temperature: -55±3°C<br>Testing time: 500h<br>Measurement at 24±2 hours after test conclusion.  |

Note: \*Use max. or min. temperatures according Würth Elektronik data sheet (current version) 30 pcs of each DUT (Device Under Test)

**DATA SHEET CHANGE:**

Yes

No